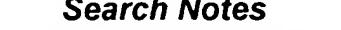


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/625,100	MUNNE, SANTIAGO
	Examiner Thaian N. Ton	Art Unit 1632

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner